
Cadence Virtuoso Report Group B

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August 3, 2026

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Introduction to Cadence Hands-on

c ā d e n c e

- Cadence one of “Big Three” Electronics Design Automation (EDA) tools provider globally
- EDA tools interface foundry processes and MAPS designers
- Cadence allows you to discover “unknown unknowns” of a circuit
- ...Cadence itself has many “unknown unknowns” to designers, regarding EDA tools
- Hands-on exercise consisted of 6 exercises

Ideal models

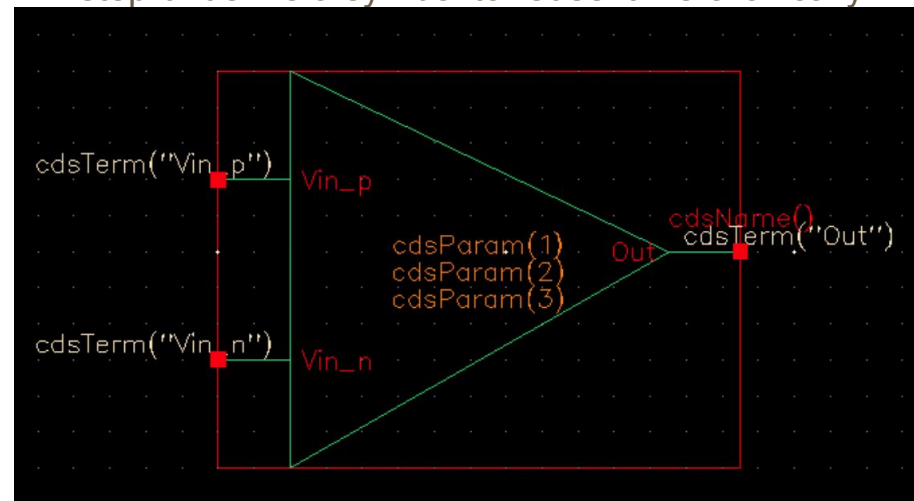
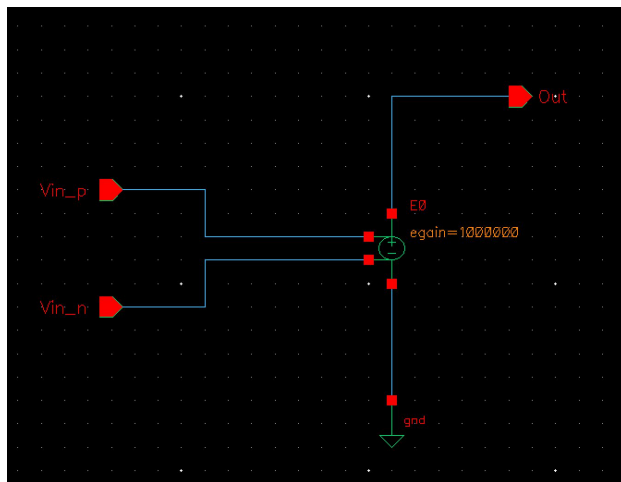
Ideal Operational Amplifier
Ideal Charge Sensitive Amplifier
Ideal CSA with feedback resistor

Transistor based

Transistor design of a simple
CSA Amplifier
Full CSA simulation
Layout of the CSA Amplifier

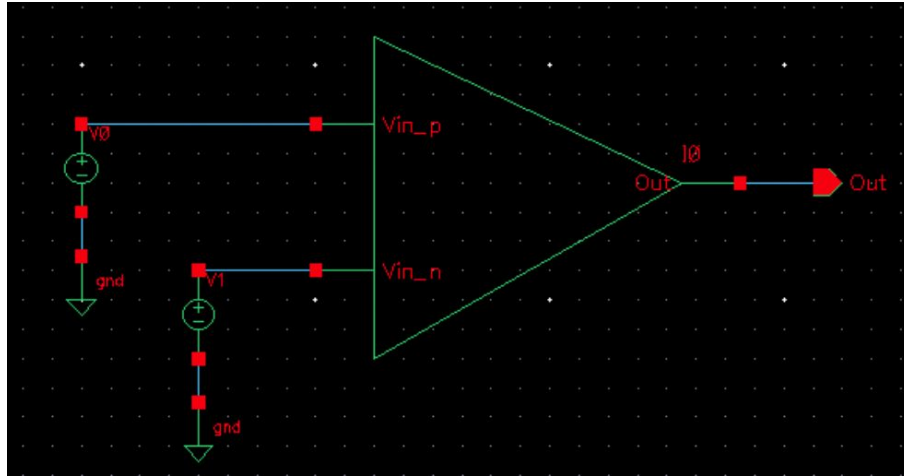
Step 1: Ideal Operational Amplifier

- Ideal Operational Amplifier
 - Theoretical electronics device which amplifies difference between two input voltages
 - Key feature infinite gain, infinite input impedance, and zero output impedance
- Main learning goals: learning how to use Virtuoso
 - step a: create a ideal op-amp
 - step b: define a symbol to reuse it hierarchically

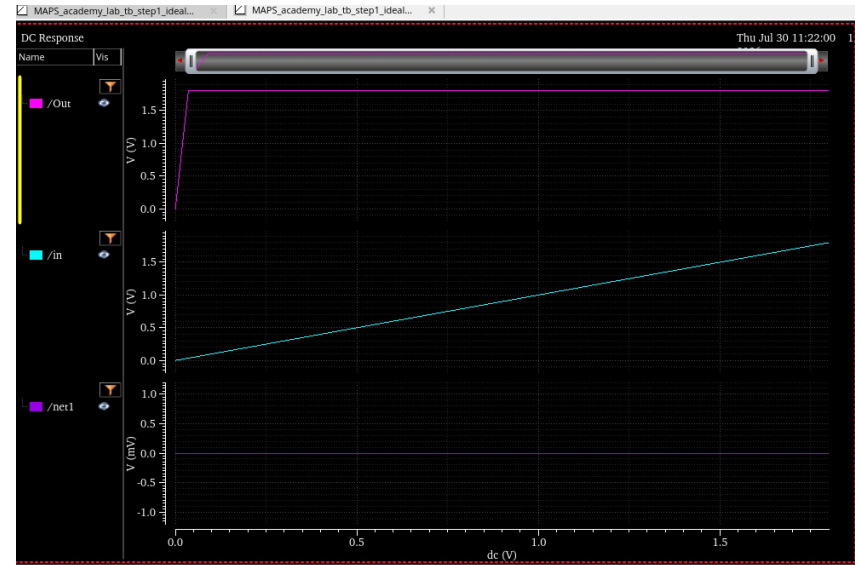


Step 1: Ideal Operational Amplifier

- step c: create a test bench by adding DC source



- step d: run simulation to characterize op-amp by sweeping dc voltages

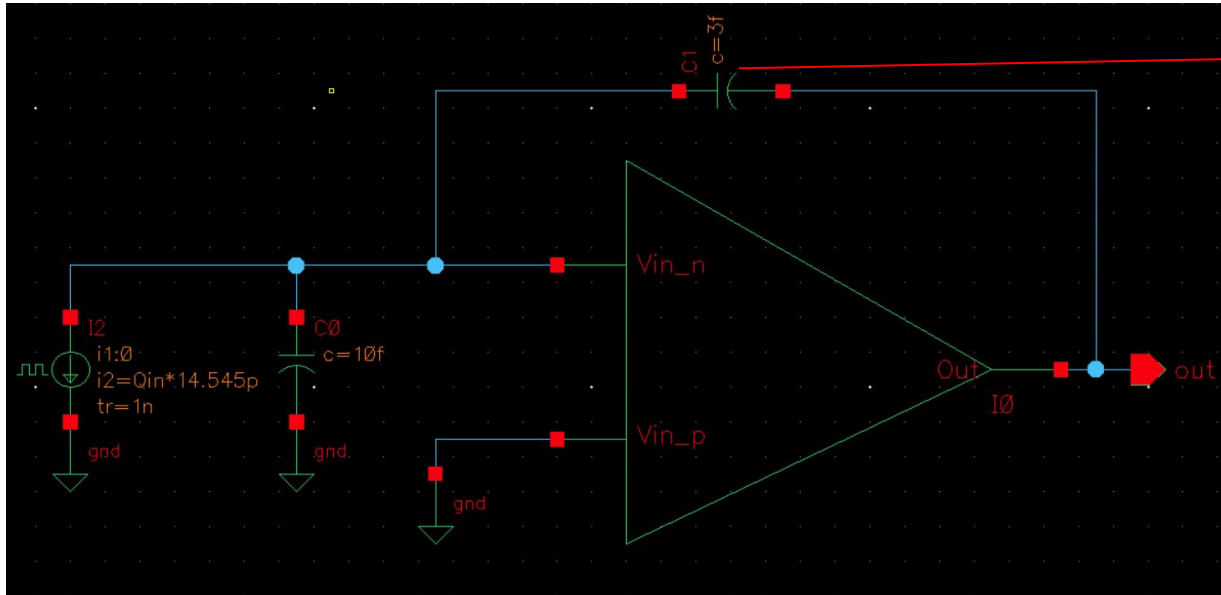


Rest of the hands-on session follows very similar pattern with designing something, creating a symbol, using it downstream in test bench simulation and characterizing properties

Step 2: Ideal Charge Sensitive Amplifier

Goal: to build an ideal charge sensitive amplifier

- A specialized circuit that converts an input charge pulse into a proportional voltage output
- Took the ideal op-amp and added a feedback capacitor



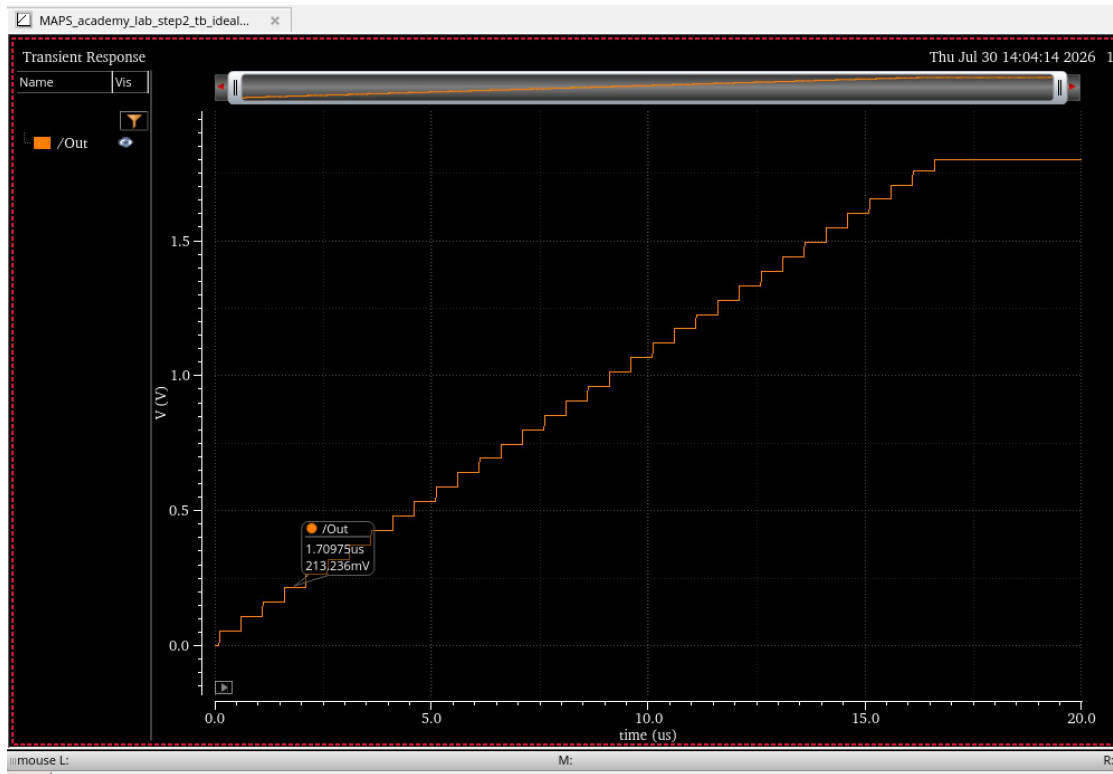
Feedback capacitor

$$V_{out} = -Q_{in}/C_f$$

Feedback pins the input node near 0V, so no charge can accumulate on C0, it's all forced onto C1 instead, which is why the output only depends on C1.

Step 2: Ideal Charge Sensitive Amplifier

- Ran simulation of ideal CSA to look at the behavior of the circuit over time



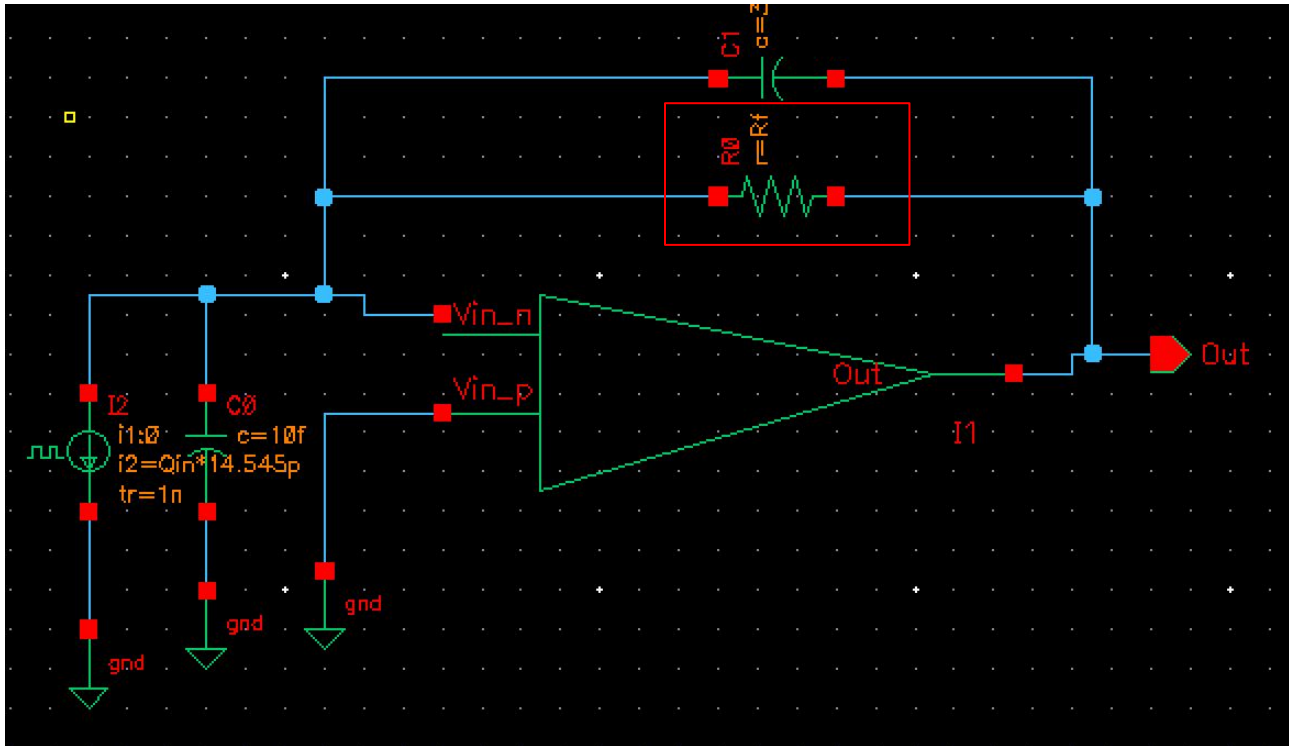
- Each pulse has 1ns rise time
- After 1ns output voltage jumps by constant amount as CSA integrates per pulse
- No reset in circuit, output voltage continuously rising

Step 3: Ideal CSA with feedback resistor

Goal: to build an ideal charge sensitive amplifier with feedback resistor

$$V_{out}(t) = \frac{Q_{in}}{C_f} e^{-t/\tau}$$
$$\tau = R_f C_f$$

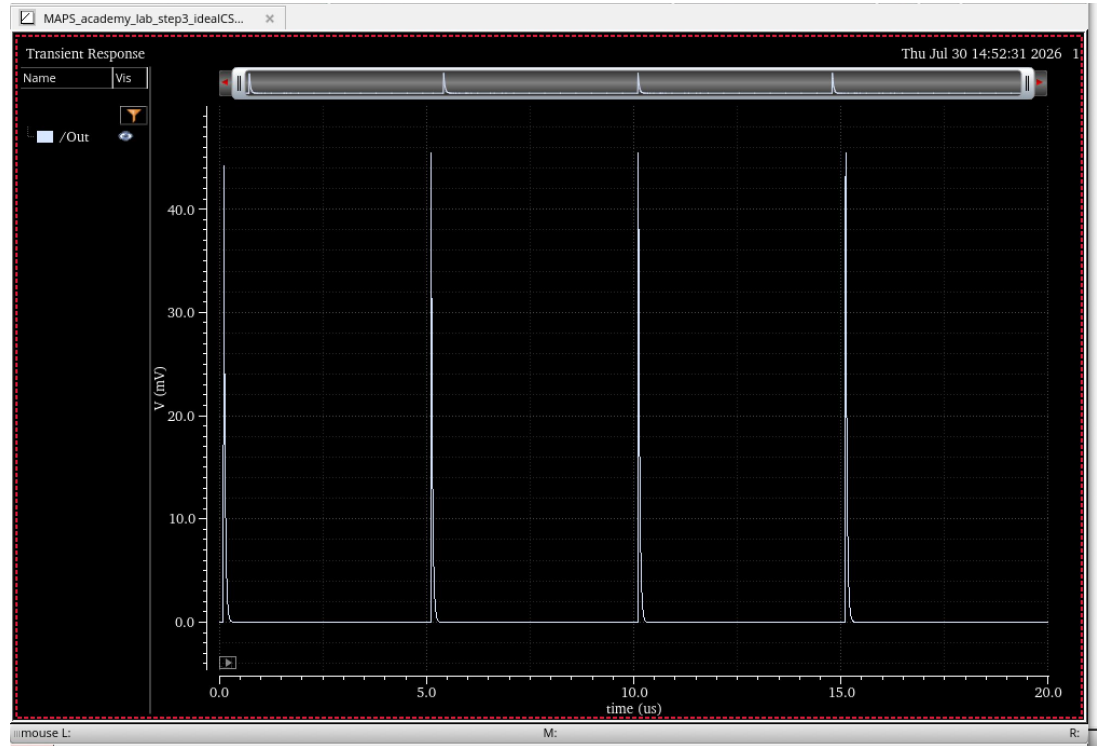
Feedback resistor plays an important role in regulating V_{out}



Step 3: Ideal CSA with feedback resistor

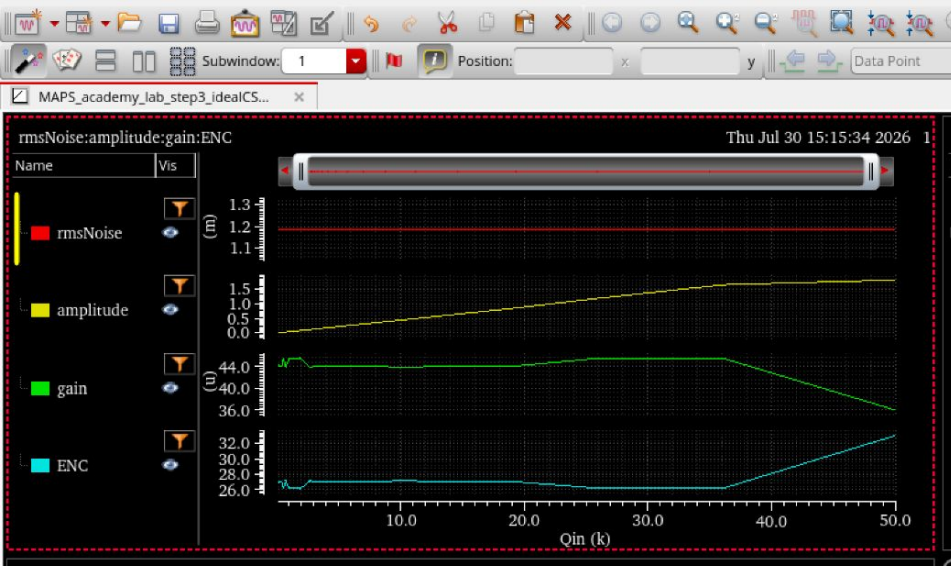
$Q_{in}=1000$, $R_f=10M$

- R_f now resets output voltage per pulse
- Transient voltage shows sharp rise and exponential decays



Step 3: Ideal CSA with feedback resistor

Varying Q_{in} , $R_f=10M$

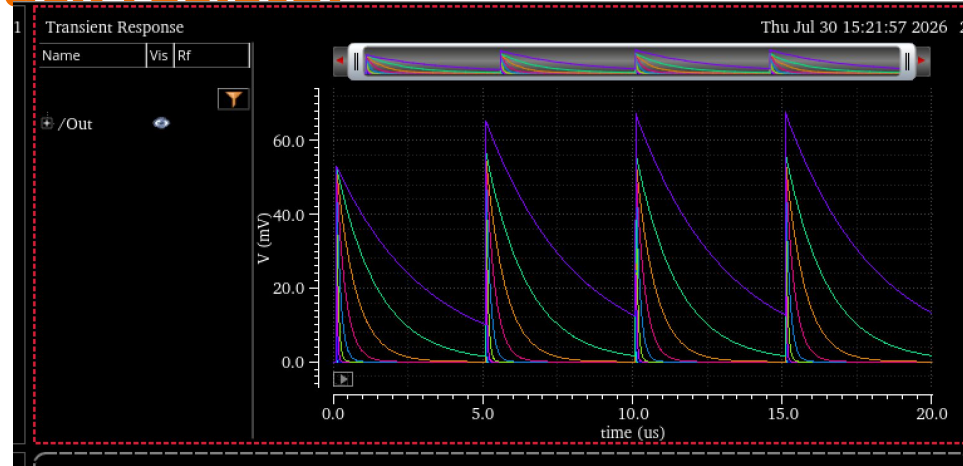
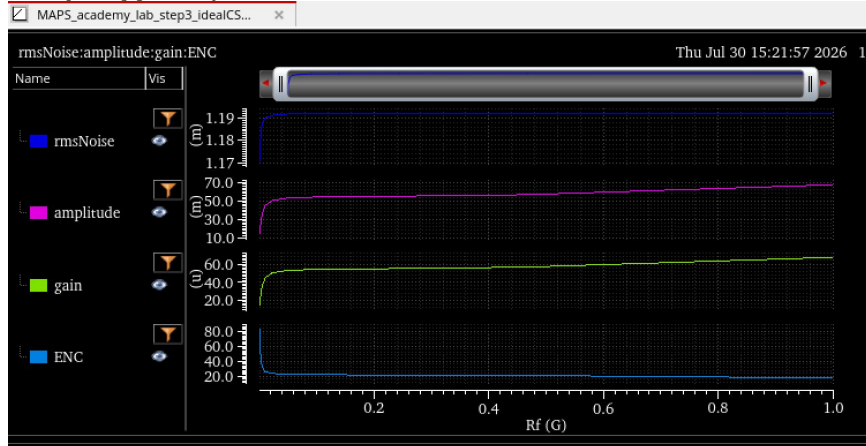


After a certain increase in Q_{in} , gain decrease, ENC increase due to saturation of V_{out}

- Signal processing parameters defined
 - **rmsNoise:** sqrt of output-referred noise power spectral density 1Hz to 1GHz
 - **Amplitude:** $y_{\max}(VT("/out")) - y_{\min}(VT("/out"))$
 - **Gain:** $\text{amplitude}/Q_{in}$
 - **Equivalent noise charge (ENC):** $\text{rmsNoise}/\text{gain}$
 - Main figure of merit
 - How much input charge would it take to produce an output fluctuation equal to the noise floor?

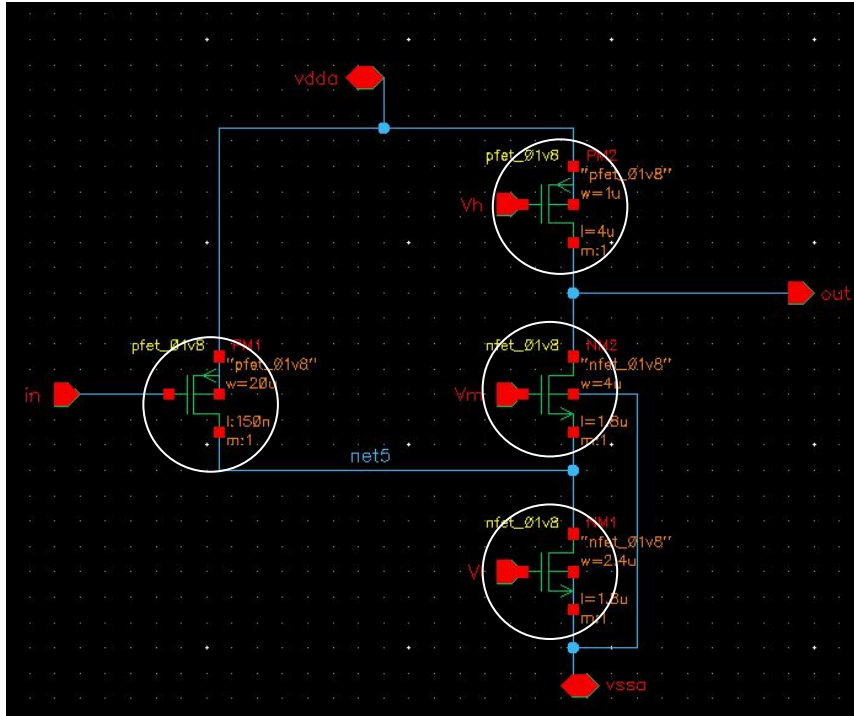
Step 3: Ideal CSA with feedback resistor

Varying R_f , $Q_{in} = 1000$



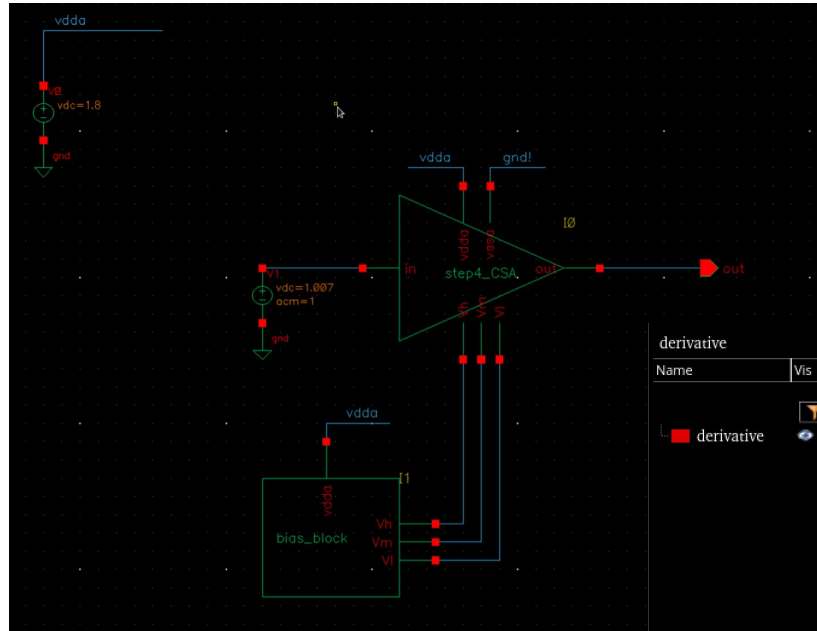
- Large R_f lower equivalent noise charge (thus better)
- But large R_f , slower discharge, more impacted by pileup

Transistor based - Simple CSA Amplifier

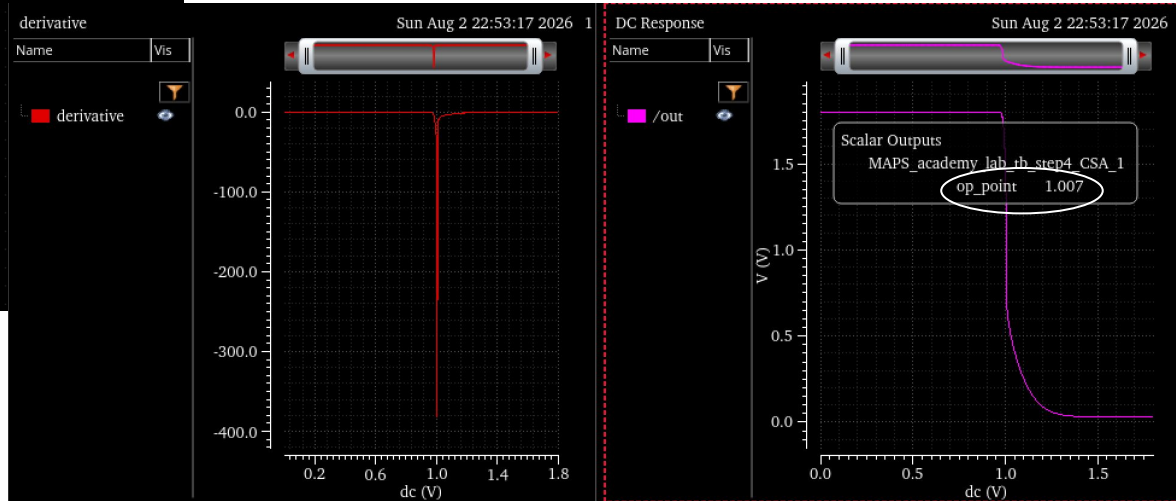


- Transistor-level CSA using Sky130 MOSFETs

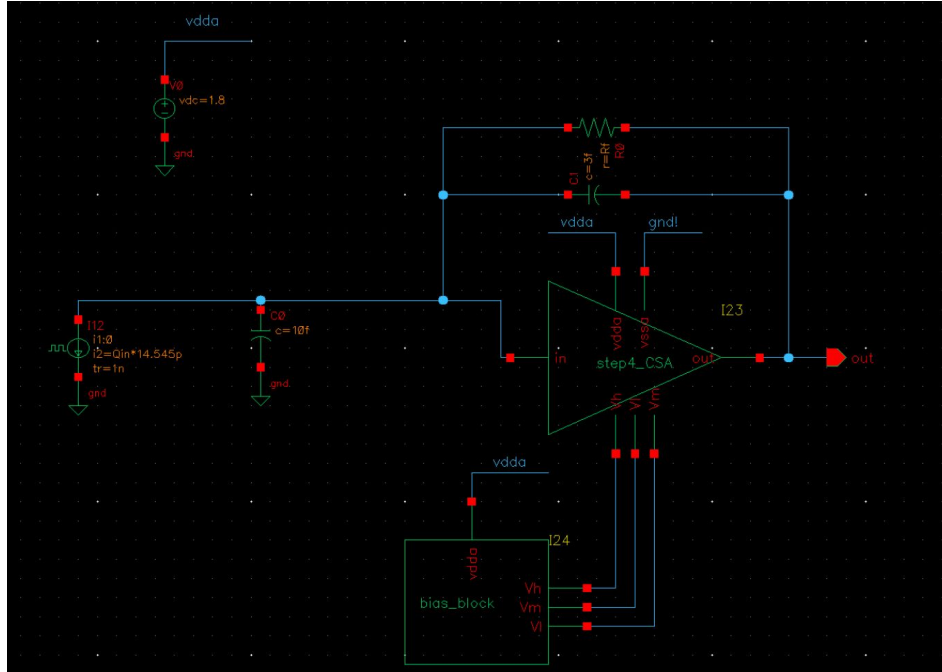
Transistor based - Simple CSA Amplifier



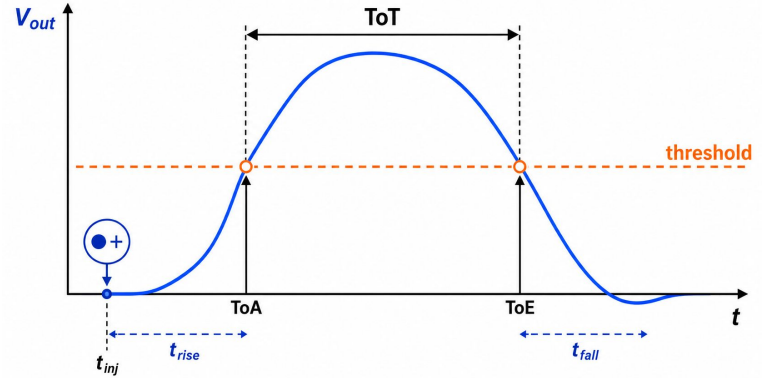
- Transistor-level CSA using Sky130 MOSFETs
- Add the bias block and perform DC analysis
- Optimal DC bias point corresponds to the maximum small-signal gain.
- The highest gain is identified from the maximum slope of the DC transfer characteristic.



Transistor based - Full CSA simulation

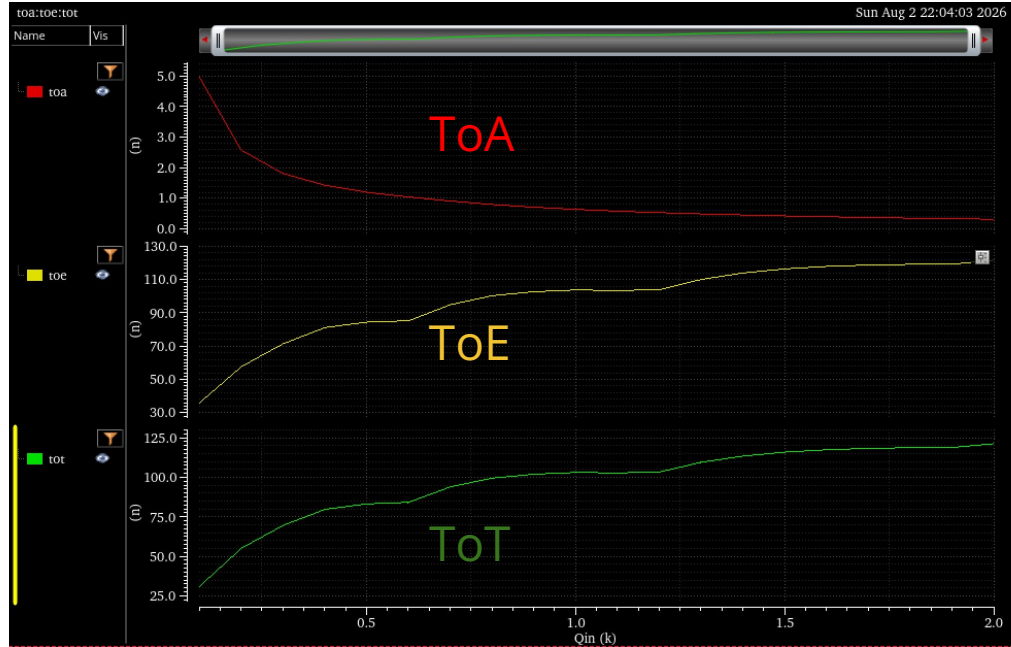


- Replace the ideal op-amp with the transistor CSA
- Add the bias block and reuse the feedback network
- Sweep $Q_{in} = 100\text{--}2000\text{ e}^-$ (step 100 e^-)
- Measure ToA, ToE and ToT



- ToA: first threshold crossing; sets time-walk behavior.
- ToE: falling-edge crossing after the pulse recovers.
- ToT = ToE - ToA: proxy for pulse amplitude / charge.

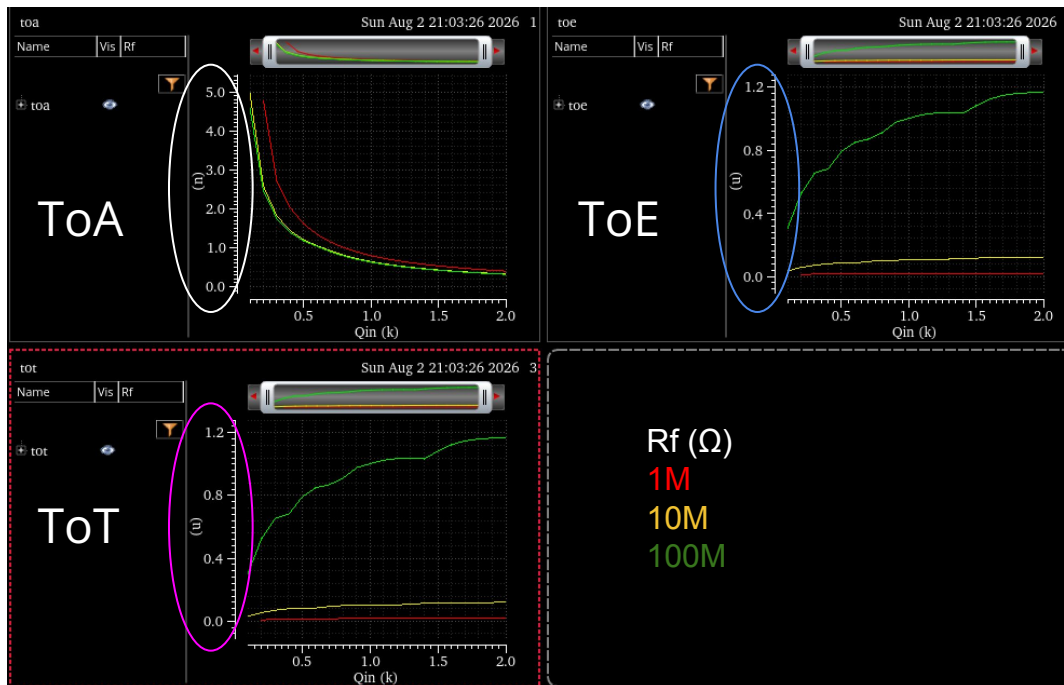
Transistor based - Full CSA simulation



Effect of Injected Charge

- Increasing Q_{in} produces an earlier threshold crossing, reducing ToA.
- Strong ToA dependence at low Q_{in} indicates significant time walk for small signals.
- Larger pulses remain above threshold longer, causing both ToE and ToT to increase.
- At high Q_{in} , the ToT response becomes less sensitive to additional charge

Transistor based - Full CSA simulation

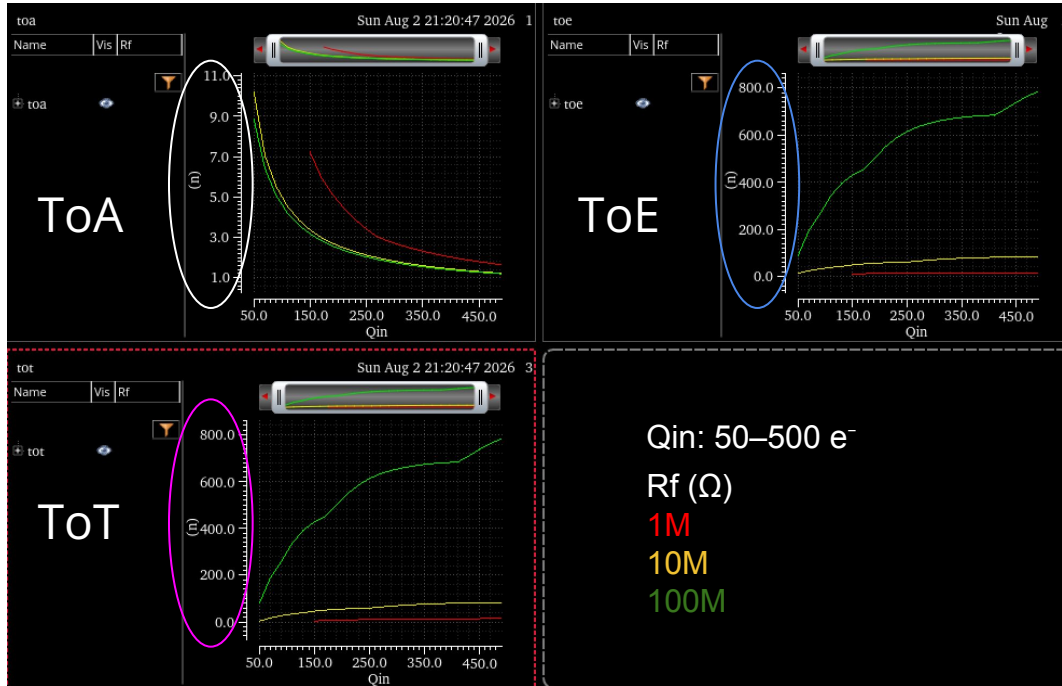


Effect of Feedback Resistance

- ToA changes little with R_f , showing minimal impact on leading-edge timing.
- Increasing R_f delays pulse recovery, resulting in a larger ToE.
- Higher R_f extends the pulse width, leading to a longer ToT.

- Low R_f : fast reset and better high-rate performance.
- High R_f : longer signal duration but greater pile-up risk

Transistor based - Full CSA simulation

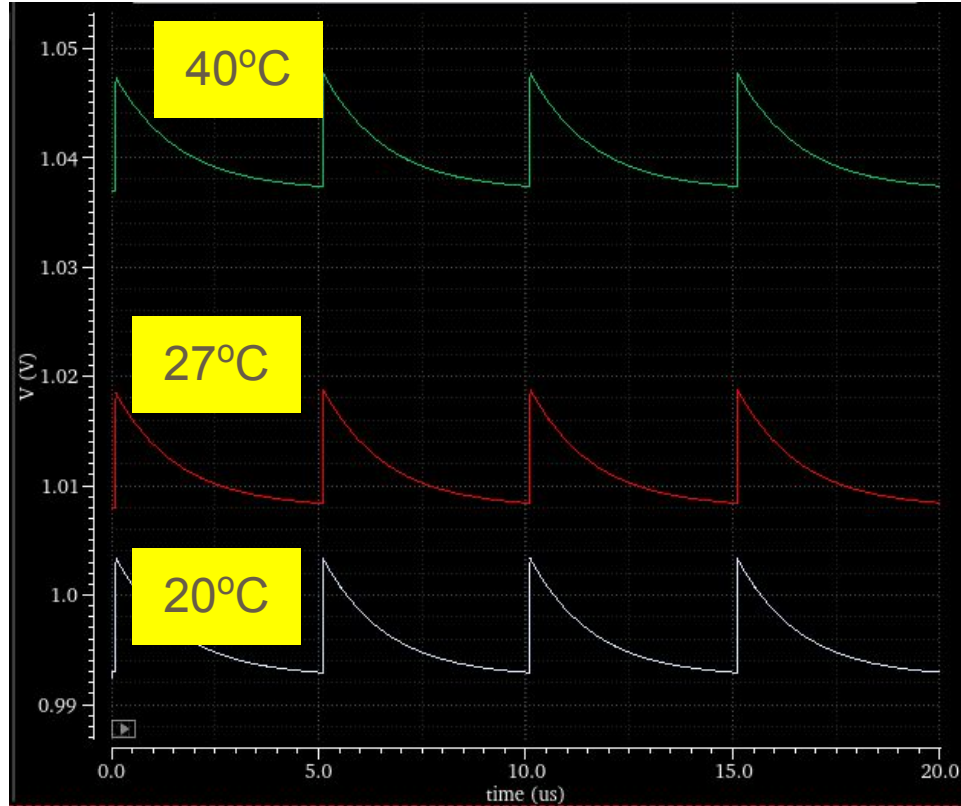


Low-Charge Performance (50–500 e^-)

- Low Q_{in} exhibits significant time walk, as small signals cross the threshold later
- ToT decreases for smaller signals, reflecting the reduced time above threshold
- Higher R_f improves low-charge sensitivity by extending the pulse above threshold
- The low- Q_{in} region defines the practical detection limit of the CSA

Schematic Output Simulation Performance - PVT

Small voltage range in output peaks lead to very strong temperature dependence.

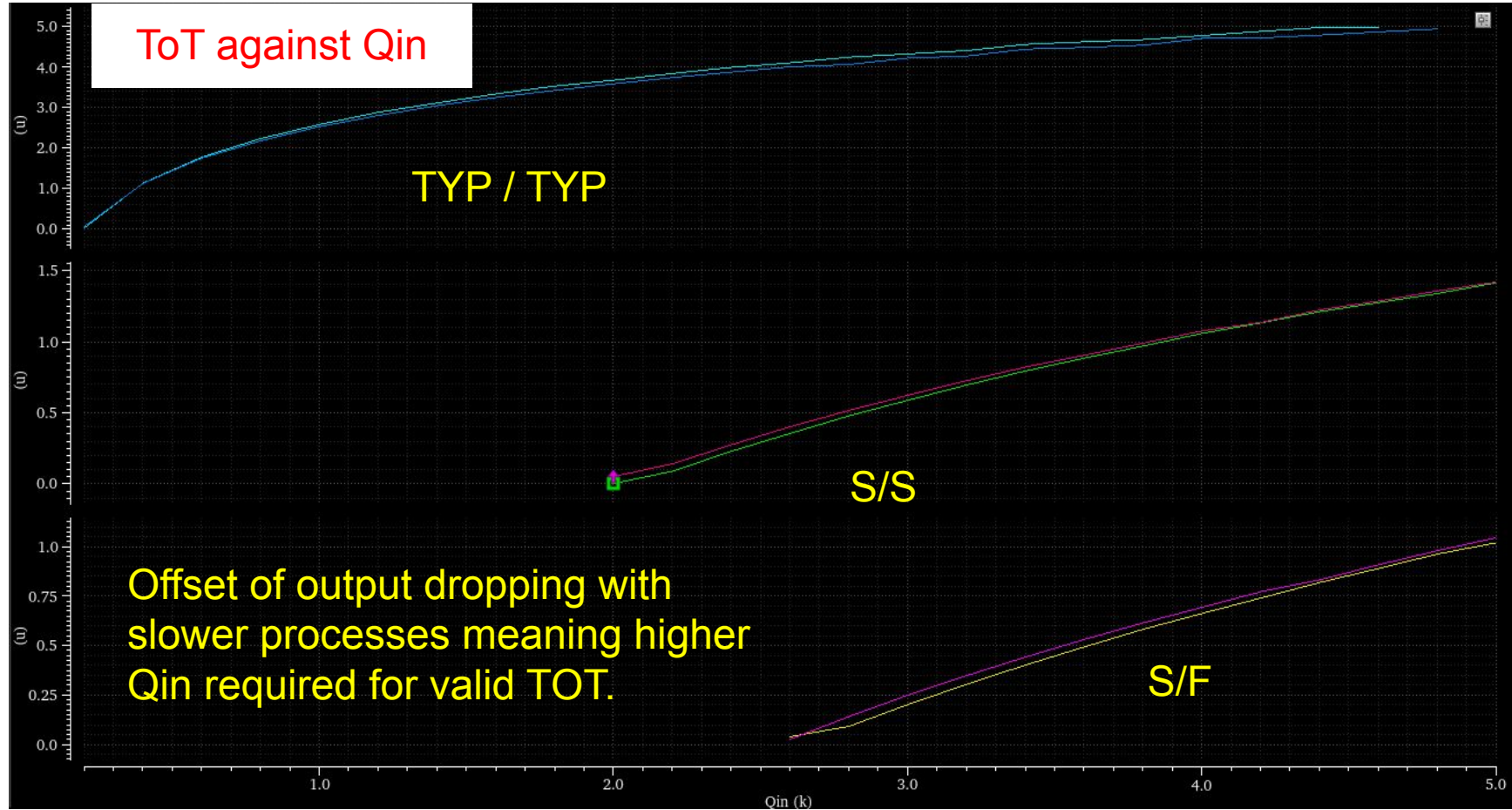


Constant charge injected of 200 e-

Same transistor process corner
(typical NMOS / typical PMOS)

Offset is highly
temperature-dependent.

Schematic Simulation Performance - PVT



Layout

Transistor channels follow one direction

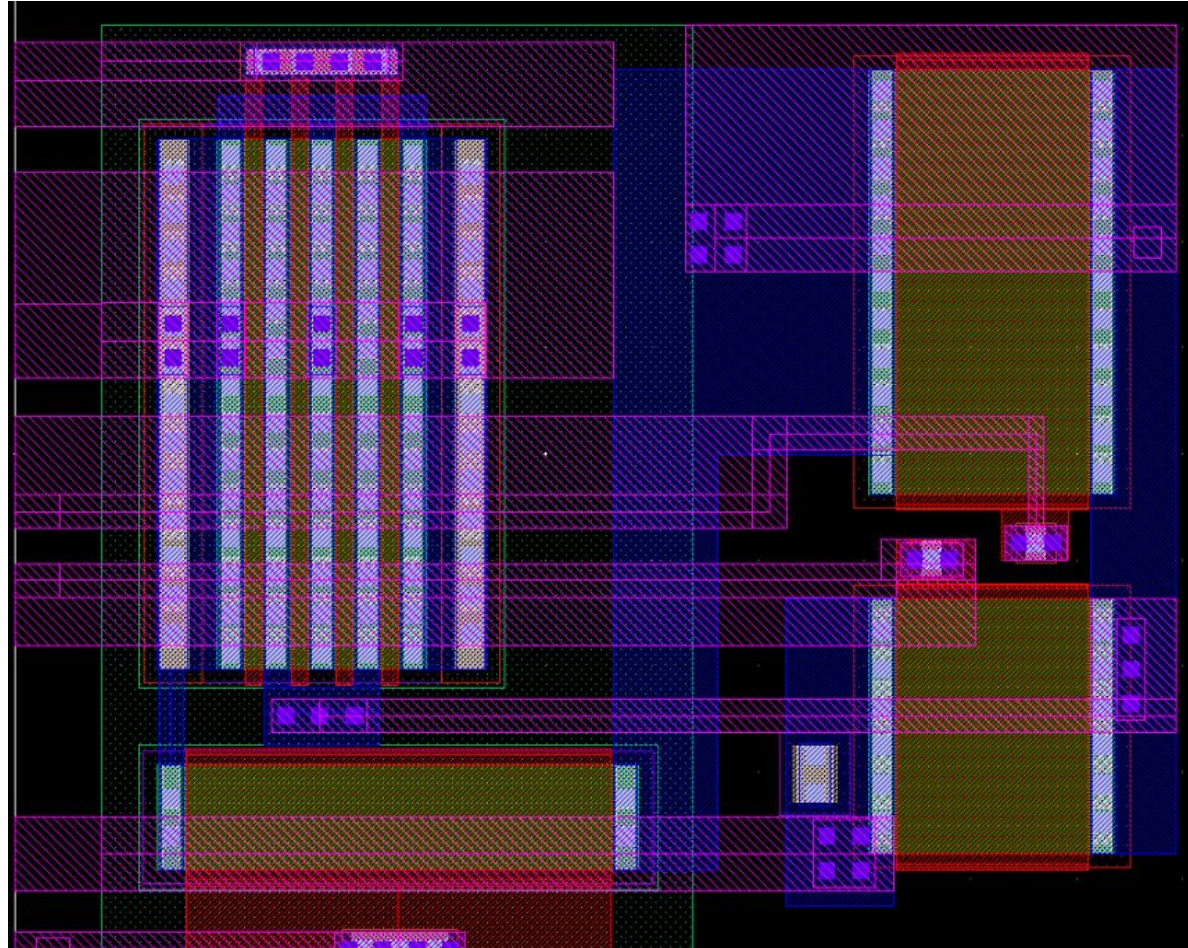
Metal 2 tracks mostly follow one direction

Minimum of two cuts per via for redundancy and .

Large analog metal tracks to reduce resistance and meet local metal density rules.

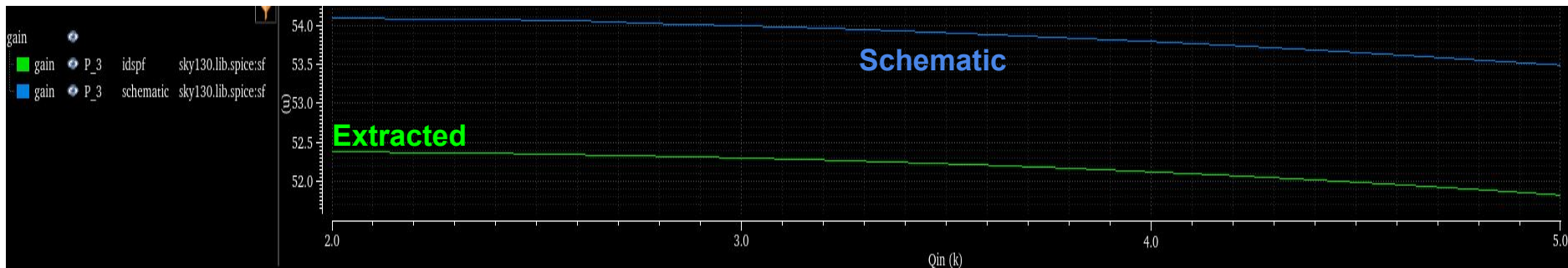
Large power supply metal 2 routing for good via connection from higher-level design.

More than minimum metal spacing between tracks for higher yield (~2x minimum).



Layout Extraction to IDSPF

- Layout introduces parasitics: resistances, capacitances, inductances etc.
- These can slow circuits, reduce power in regions, and impact performance
- Comparison needed before and after

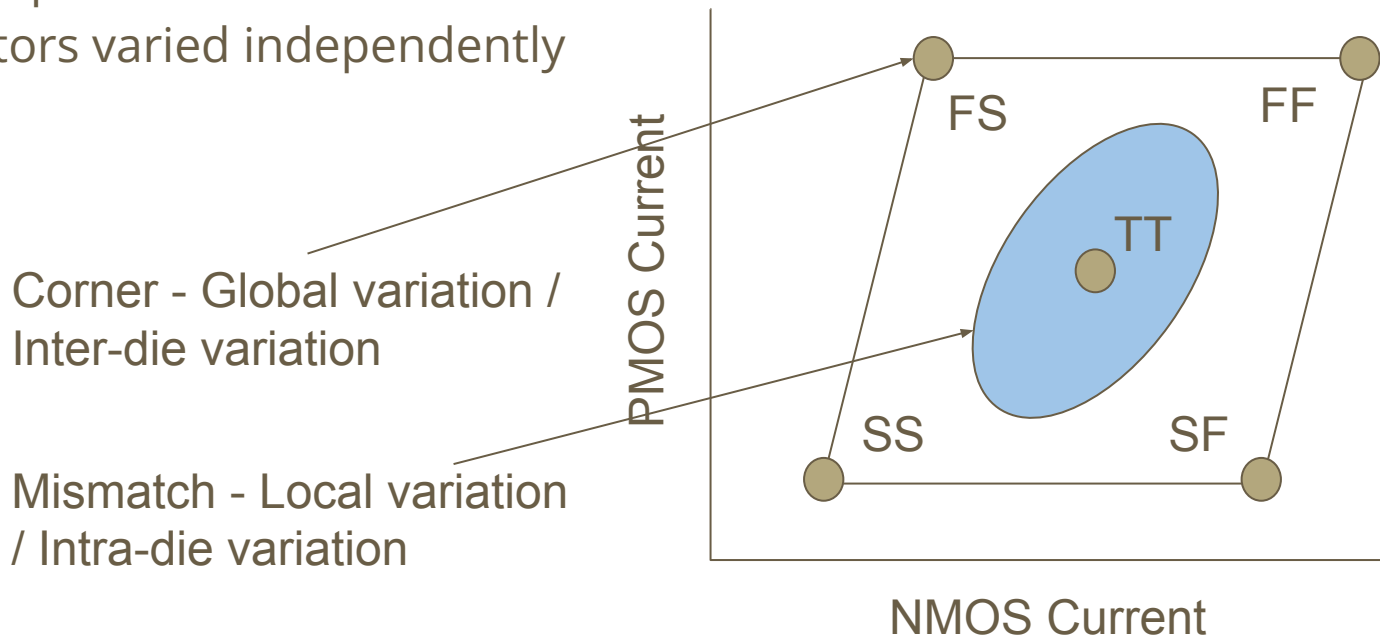


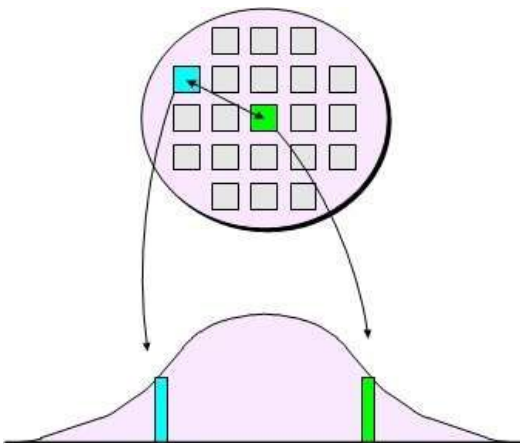
Schematic has consistently higher gain than for the extracted layout. Example given for S/F corner, but true for all.

The open loop gain of amplifier is likely decreasing with increasing charge - causing gain to drop.

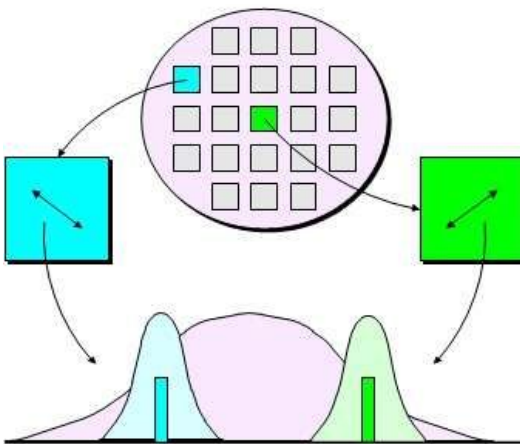
Next Step - Monte Carlo Simulation

- Monte Carlo provide insight to statistical mismatch between devices
- Includes process and mismatch variation
- Transistors varied independently

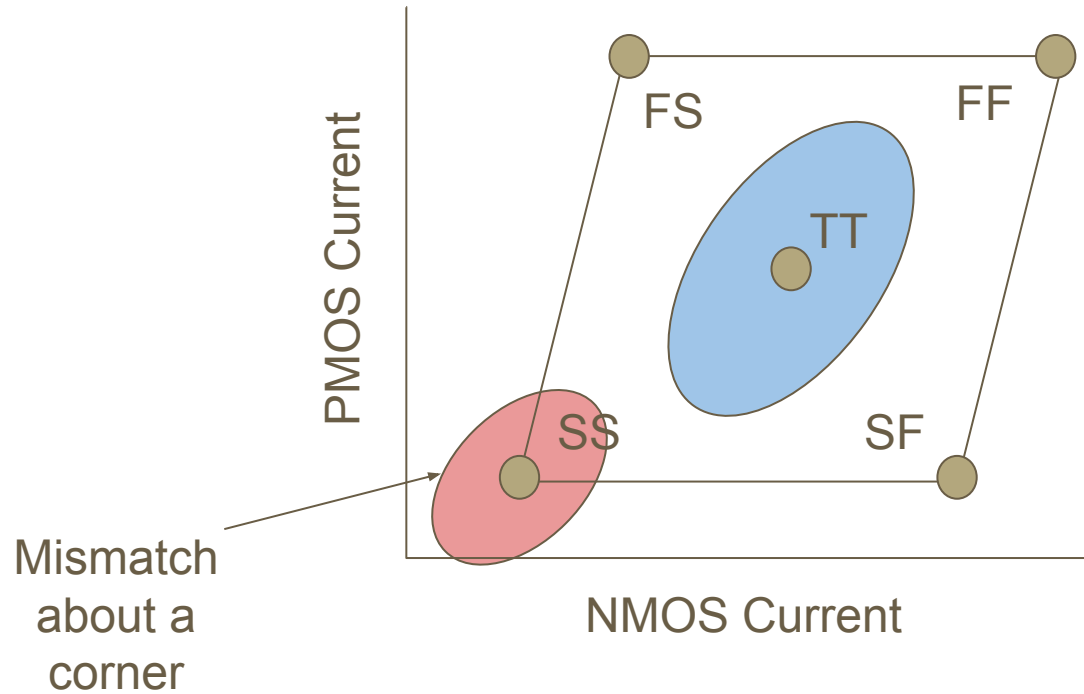




Inter-die variations



Intra-die variations



Maxfield, C. M. (2010, December 3). *Overcoming 32/28-nm IC implementation challenges*. EDN.
<https://www.edn.com/overcoming-32-28-nm-ic-implementation-challenges/>

Summary

- Mini “chip flow” in Cadence Virtuoso with CSA
- Ideal / “Behavioural” → Transistor-level schematic → simulation → layout → post-layout simulation
- ADE environment for expression building and extracting circuit parameters
- Corner sweep to explore effects of process variation